Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
09/614,660	KIROVSKI ET AL.
Examiner	Art Unit
Christopher A. Revak	2131

	SEARCHED		
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
380	200-203	4/21/2005	CR
380	205,210	4/21/2005	CR
380	236-238	4/21/2005	CR
380/44,46,2 252	14,243,246, ,253	4/21/2005	CR

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
BRS Text Search USPAT, DERWENT, JPO, EPO, IBM TDB, US PGPUB, USOCR	9/14/2005	CR
DIALOG Text Search COMPSCI, ELECTRON, SOFTWARE	9/14/2005	CR
101 Help Panel	9/14/2005	CR
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Search Notes (continued)

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	SEARCHED		
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
382	232,248	4/21/2005	CR
382	250,276	4/21/2005	CR
382	280	4/21/2005	CR
713.	/176	4/21/2005	CR

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR